

Search Notes

Application/Control No.

10/808,560

Examiner

Gopal C. Ray

Applicant(s)/Patent under
Reexamination

OHNISHI, MAKOTO

Art Unit

2111

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|------------------------|-----------|----------|
| 710 | 305,313,300,33,110,316 | 1/11/2006 | GCR |
| 715 | 735 | 1/11/2006 | GCR |
| 365 | 189.04 | 1/11/2006 | GCR |
| 711 | 155,203 | 1/11/2006 | GCR |
| 709 | 223,238 | 1/11/2006 | GCR |
| 709 | 208,213 | 1/11/2006 | GCR |
| 709 | 253 | 1/11/2006 | GCR |
| 370 | 434,230 | 1/11/2006 | GCR |
| 370 | 401,402 | 1/11/2006 | GCR |
| 370 | 351,257 | 1/11/2006 | GCR |
| 370 | 244,464 | 1/11/2006 | GCR |
| 370 | 492 | 1/11/2006 | GCR |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts) | 1/10/2006 | GCR |
| WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts) | 1/11/2006 | GCR |
| EAST: USPT (see search history printouts) | 1/10/2006 | GCR |
| NPL: IEEE Xplore (see search history printouts) | 1/10/2006 | GCR |
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